

RELIABILITY DATA **LT1316 / LT3460 / LT3461 / LT3464 / LT3471 / LT3472**

8/21/2006

• OPERATING LIFE TEST

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS ⁽¹⁾ AT +125°C	NUMBER OF ⁽²⁾ FAILURES
SOIC/SOT/MSOP	770	9714	0439	766.50	0
	770			766.50	0

• PRESSURE COOKER TEST AT 15 PSIG, +121°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE HOURS	NUMBER OF FAILURES
SOIC/SOT/MSOP	2,705	9913	0620	116.21	0
QFN/DFN	216	0416	0535	57.60	0
	2,921			173.81	0

• TEMP CYCLE FROM -65°C to +150°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
SOIC/SOT/MSOP	10,482	9707	0620	1,125.72	0
QFN/DFN	220	0416	0535	73.50	0
	10,702			1,199.22	0

• THERMAL SHOCK FROM -65°C to +150°C

PACKAGE TYPE	SAMPLE SIZE	OLDEST DATE CODE	NEWEST DATE CODE	K DEVICE CYCLES	NUMBER OF FAILURES
SOIC/SOT/MSOP	2,247	9950	0620	255.10	0
QFN/DFN	218	0416	0535	72.50	0
	2,465			327.60	0

(1) Assumes Activation Energy = 1.0 Electron Volts

(2) Failure Rate Equivalent to +55°C, 60% Confidence Level = 2.40 FITS

(3) Mean Time Between Failures in Years = 47,532

Note: 1 FIT = 1 Failure in One Billion Hours.